Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/021,719	TANAKA, KOICHIRO
Examiner	Art Unit
DUNG A. LE	2818

SEARCHED					
Class	Subclass	Date	Examiner		
438	166	3/18/2005	DLE		
	487				
	308				
	378				
	795				
219	121.65	/	j		
	121.76	$\bigvee$	1		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
IEEE,PGPUB,JPO,EPO,EAST, IMB	3/18/2005	DLE		
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